

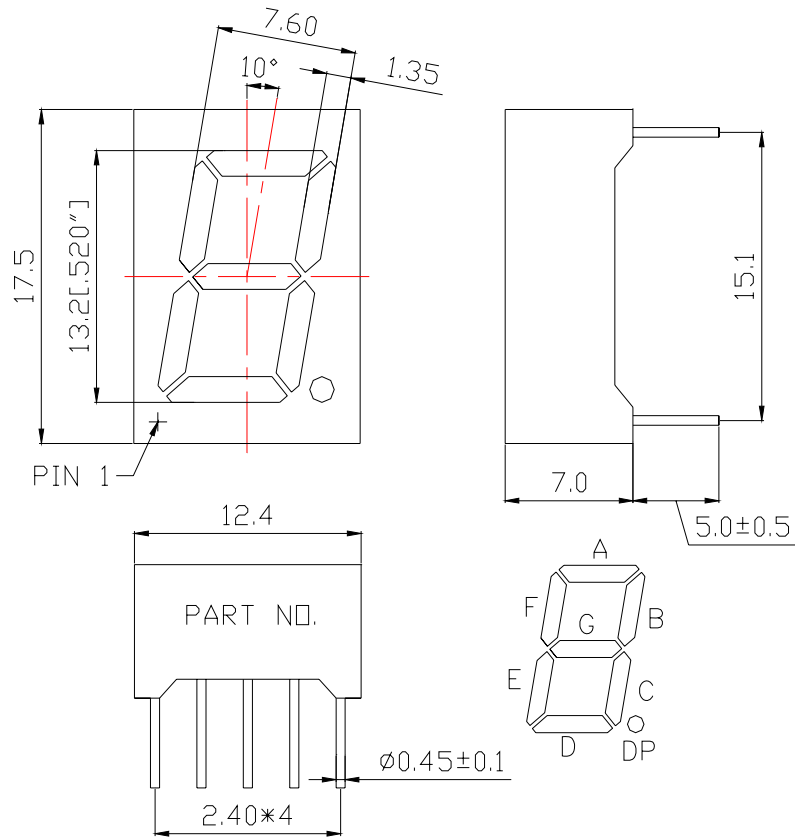
# **WCN1-1052SR-A11**

## **SPECIFICATION**

<b>WCN</b>			<b>CUSTOMER Confirmed</b>
<b>Prepared by</b>	<b>Checked by</b>	<b>Approved by</b>	
<b>Fei</b> <b>2016-4-20</b>	<b>Athena</b>	<b>William</b>	
<b>REVISION RECORD</b>			

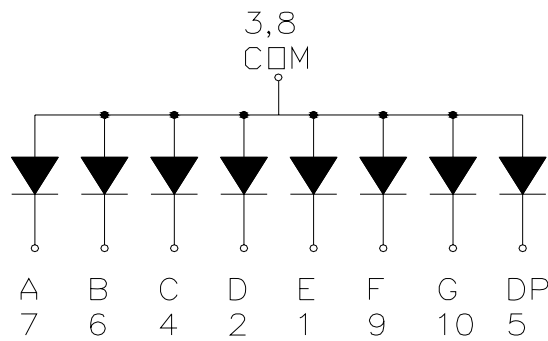
**REVISION: A0**

### Outer Dimension:



Notes: Unless otherwise stated, The tolerance is  $\pm 0.25$ mm.

### Circuit Diagram:



### Pin Connection:

PIN NO.	CONNECTION	PIN NO.	CONNECTION
1	Cathode E	6	Cathode B
2	Cathode D	7	Cathode A
3	Common Anode	8	Common Anode
4	Cathode C	9	Cathode F
5	Cathode DP	10	Cathode G

■ **Features:**

- High Reliability
- Color:Red
- Low Power Requirement
- Easy Assembly

■ **Description:**

- Single Digit Display
- Digit Height:13.2mm(0.52" )
- Gray Face and Milky Segment

■ **Absolute Maximum Rating (Ta=25°C):**

Parameter	Symbol	Condition	Color	Rating	Units
Power Dissipation Per Segment	P <sub>d</sub>	—	Red	65	mW
Forward Current Per Segment	I <sub>F</sub>	—	Red	25	mA
Peak Forward Current Per Segment	I <sub>FP</sub>	1/10 Duty 10KHz	Red	100	mA
Reverse Voltage Per Segment	V <sub>R</sub>	—	Red	5	V
Operating Temperature Range	T <sub>opr</sub>	—	—	-35~+85	°C
Storage Temperature Range	T <sub>stg</sub>	—	—	-35~+85	°C

■ **Electrical/Optical Characteristics Rating(Ta=25°C)**

Item	Symbol	Test conditions	Location	Rating			Units
				Min.	Typ.	Max.	
Forward Voltage	V <sub>F</sub>	I <sub>F</sub> =20mA	Per Segment	—	2.00	2.60	V
Reverse Current	I <sub>R</sub>	V <sub>R</sub> =5V	Per Segment	—	—	100	μA
Luminous Intensity	I <sub>V</sub>	I <sub>F</sub> =10mA	Per Segment	—	5500	—	μcd
Peak Emission Wave Length	λ <sub>P</sub>	I <sub>F</sub> =20mA	Per Segment	—	638	—	nm
	λ <sub>D</sub>			—	633		
Spectral Line Half Width	△λ	I <sub>F</sub> =20mA	Per Segment	—	20	—	nm
Luminous Intensity Matching Ratio (Segment to Segment)	I <sub>v-m</sub>	I <sub>F</sub> =10mA	—	—	—	1.2:1	

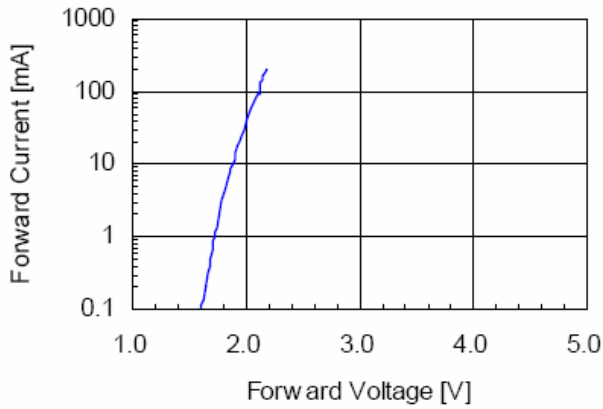
■ **Luminous Intensity Sorting: (Luminous Intensity Tolerance is +/-10%)**

Rank	Symbol	Condition	Min	Max	Unit
K	K	I <sub>F</sub> =10mA	3051	4000	μcd
L	L	I <sub>F</sub> =10mA	4001	5000	μcd
M	M	I <sub>F</sub> =10mA	5001	6100	μcd
N	N	I <sub>F</sub> =10mA	6101	7200	μcd
O	O	I <sub>F</sub> =10mA	7201	8500	μcd

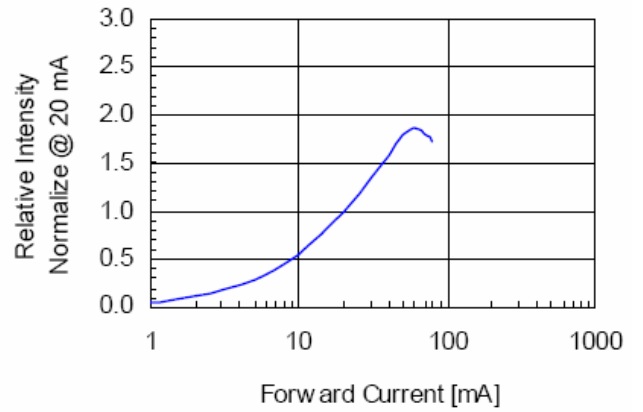
■ **Soldering Conditions: Soldering Temp. ≤+260°C, Soldering Time. ≤3sec.**  
 (at 2mm Distance from The Case of Reflector Edge)

**Typical Elector-Optical Characteristics Curve:**

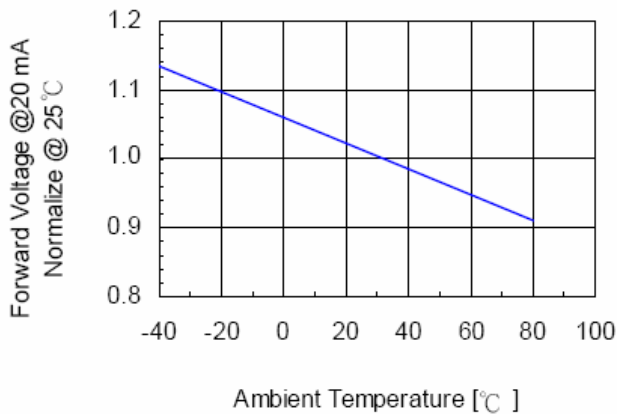
**Fig 1. Forward Current vs. Forward Voltage**



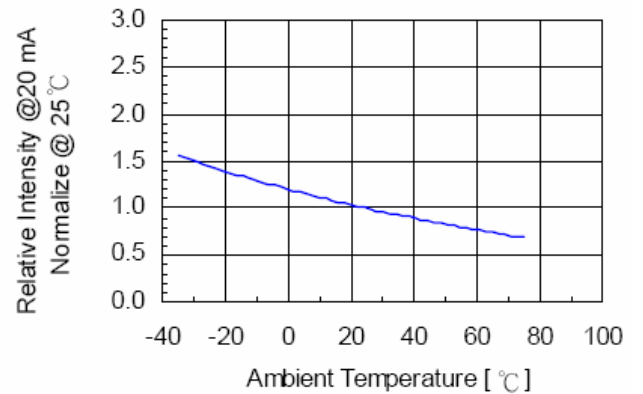
**Fig 2. Relative Intensity vs. Forward Current**



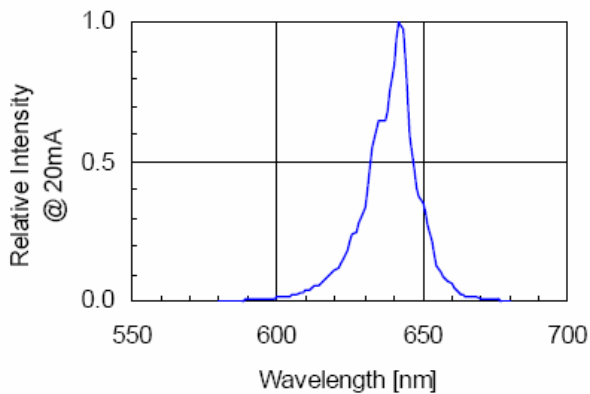
**Fig 3. Forward Voltage vs. Temperature**



**Fig 4. Relative Intensity vs. Temperature**



**Fig 5. Relative Intensity vs. Wavelength**



**LED Displays Reliability Test:**

CLASSIFICATION	TEST ITEM	DESCRIPTION AND TEST CONDITION
ENDURANCE TEST	OPERATION LIFE	EVALUATES RESISTANCE OF THE DEVICE WHEN OPERATED AT ELECTRICAL STRESS $T_a$ = UNDER ROOM TEMPERATURE $I_F = I_F \text{ max}$
	HIGH TEMPERATURE HIGH HUMIDITY STORAGE	EVALUATES MOISTURE RESISTANCE OF THE DEVICE WHEN STORED FOR A LONG TERM AT HIGH TEMPERATURE AND HUMIDITY $T_a = 65 \pm 5^\circ\text{C}$ RH=90~95%RH TEST TIME=240 $\pm$ 2Hrs
	HIGH TEMPERATURE STORAGE	EVALUATES DEVICE DURABILITY FOR LONG TERM STORAGE IN HIGH TEMPERATURE $T_a = 85 \pm 5^\circ\text{C}$ (COB: $T_a = 65 \pm 5^\circ\text{C}$ ) TEST TIME=1000Hrs(-24Hrs, +72Hrs)
	LOW TEMPERATURE STORAGE	EVALUATES DEVICE DURABILITY FOR LONG TERM STORAGE IN LOW TEMPERATURE $T_a = -35 \pm 5^\circ\text{C}$ TEST TIME=1000Hrs(-24Hrs, +72Hrs)
ENVIRONMENTAL TEST	TEMPERATURE CYCLING	EVALUATES RESISTANCE OF DEVICE AT THERMAL STRESSES OR EXPANSION AND CONTRACTION $85^\circ\text{C} \sim 25^\circ\text{C} \sim -35^\circ\text{C} \sim 25^\circ\text{C}$ 30min 5min 30min 5min 10 CYCLES(COB: $T_{\text{hot}}=65^\circ\text{C}$ , $T_{\text{cold}}=-25^\circ\text{C}$ )
	THERMAL SHOCK	EVALUATES DEVICE STRUCTURE AND STRUCTURE AND MECHANICAL RESISTANCE WHEN SUDDENLY EXPOSED AT SERVE CHANGES $85 \pm 5^\circ\text{C} \sim -35 \pm 5^\circ\text{C}$ 10min 10min 10 CYCLES(COB: $T_{\text{hot}}=65^\circ\text{C}$ , $T_{\text{cold}}=-25^\circ\text{C}$ )
	SOLDERABILITY	EVALUATES SOLDERABILITY ON LEADS OF DEVICE $T_{\text{SOL}}=230 \pm 5^\circ\text{C}$ DWELL TIME=5 $\pm$ 1sec.
	SOLDER RESISTANCE	EVALUATES RESISTANCE TO THERMAL STRESS CAUSED BY SOLDERING $T_{\text{SOL}}=260 \pm 5^\circ\text{C}$ DWELL TIME=10 $\pm$ 1sec.

**Packing method A :**

- 200 pcs / Red Expandable Polyethylene.
- 1400 pcs / Box(360\*175\*130mm).
- 8400 pcs / Carton(550\*380\*280mm).

**Packing method B :**

- 40pcs / IC Tube.
- 2160 pcs / Box(537\*175\*125mm).
- 8640 pcs / Carton(550\*380\*280mm).